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**INFORMATION DISCLOSURE STATEMENT
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Applicant: YAMADA et al

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Examiner: to be assigned

Group Art Unit: 2812

U.S. PATENT DOCUMENTS

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
ML	AR	5,929,476	07/1999	PRALL			
	BR						
	CR						
	DR						
	ER						
	FR						
	GR						
	HR						
	IR						

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available
						Enclosed	No
	JR						
	KR						
	LR						
	MR						
	NR						
	OR						
	PR						
	QR						
	RR						
	SR						

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

ML	TR	Patent Abstracts of Japan, Publ. No. JP 01 158768, Vol. 013, No. 429, 1989			
ML	UR	Patent Abstracts of Japan, Publ. No. JP 01 147860, Vol. 013, No. 407, 1989			
ML	VR	Rupp et al., "Extending trench DRAM technology to 0.15 μ m groundrule and beyond", IEDM Technical Digest, 1999, pg. 33-36			
ML	WR	Gruening et al., "A novel trench DRAM cell with a <u>VERT</u> ical access transistor and <u>Bur</u> ied <u>ST</u> rap (VERI BEST) for 4Gb/16Gb", IEDM Technical Digest, 1999, pg. 25-28			
ML	XR	"High density vertical DRAM cell", IBM Technical Disclosure Bulletin, Vol. 29, No. 5, 1986, pg. 2335-2340			
	YR				

Examiner

Date Considered:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.